# **RAK833 LoRa Gateway**

## Mini PCIE Module Reliability Test Report

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After updating new version, this document without prior notice.

## 1. Test sample description

| Item           | <b>Description</b> Remarks         |            |  |
|----------------|------------------------------------|------------|--|
| Sample type    | RAK833 PCIE LoRa Gateway module    | RAK833-EVB |  |
| Sample qty     | 2 PCS                              |            |  |
| HW version     | V1.1                               |            |  |
| SW version     | ramips-mt7628-mt7628-squashfs-sysu |            |  |
|                | pgrade 2018050-2.bin               |            |  |
| Test applicant | Farce.chen                         |            |  |
| Test date      | 20180611                           |            |  |

# 2. Test Stage

| Test unit  |                           |
|------------|---------------------------|
| Test stage | □Sample ☑ Small-batch     |
|            | □Medium-batch □Mass-batch |

### 3. Test Result



# 4. Test Item

| Test Item |                             | Test Result | Remarks |
|-----------|-----------------------------|-------------|---------|
|           | High temperature storage    | NA          |         |
|           | Low temperature storage     | NA          |         |
| Item 1    | Constant temperature and    | pass        |         |
|           | constant humidity storage   |             |         |
|           | High and low temperature    | pass        |         |
|           | test                        |             |         |
|           | Hygrothermal of alternating | NA          |         |
|           | Thermal Shock Test          | Pass        |         |
| Item 2    | Vibration test              | NA          |         |
|           | Drop Test                   | NA          |         |
|           | ESD test                    | NA          |         |
| Item 3    | ROSH test                   | NA          |         |
|           | Aging test                  | pass        |         |
|           | Packaging and storage test  | NA          |         |
|           | Packaging pressure test     | NA          |         |
| Item 4    | Packaging vibration test    | NA          |         |
|           | Alcohol test adhesion test  | NA          |         |
|           | Fireproof test of material  | NA          |         |

### 5. Test standard

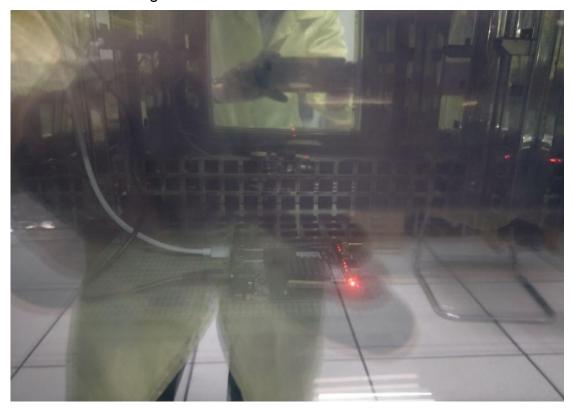
| Product reliability test report |  |  |                                 |                         |  |
|---------------------------------|--|--|---------------------------------|-------------------------|--|
| Product stage                   | □Sample ☑ Small-batch □Mediu   | ım-batch □Mass-b   | atch                            |                         |  |
| Start time                      | Close time   | Test item name   |                                 |                         |  |
| 2018-06-11                      | 2018-06-13   | High and low temperature reliability test                            |                                 |                         |  |
| Product name                    | Product model  | Test qty   | Test appli                      | Test applicant          |  |
| LoRa Gateway                    | RAK833   | KK833 2 Farce.chen   |                                 |                         |  |
| Test Result                     | ☑Pass □Not Pass □Pass Conditionally  |  |                                 |                         |  |
| Test purpose                    | Verify the electrical performance reliability of products in high and low temperature environment.   |  |                                 |                         |  |
| Test condition                  | Put the normal position into the high  1. High temperature test: the heating temperature of the product reaches after the temperature is stable.  2. Low temperature test: set at low to temperature of the product reaches temperature is stable.  **C **TEST POINT 1**  24 **-20**  -20**  TEST POINT 1**  24 **-20**  -24 **-20**  -25 ** | g rate is 1 degrees /N<br>30 degrees centigrad<br>emperature from 80 | IIN, so that the e, and the 24H | is continuously tested  |  |
| Apparatus /                     | High and low temperature box / Note  | hook computer  |                                 |                         |  |
| equipment                       | Trigit and low temperature box / Note  | book computer  |                                 |                         |  |
| Test result                     | After testing, the appearance, mecha   | anical properties, elec  | ctrical properties              | s, and other properties |  |
| judgment                        | of the samples are normal.   |  |                                 |                         |  |

# 6. Test process

1. Put the module into the test box:



2. Module in running state:



#### 3. Running test results:

```
1 COM35
status -> 4:2:
TX finished
INFO: tx_start_delay=1495 (1495.500000) - (1497, bw_delay=1.500000, notch_delay=0.000000)
Sending packet #127, rf path 0, return 0
status -> 4:2:
TX finished
INFO: tx_start_delay=1495 (1495.500000) - (1497, bw_delay=1.500000, notch_delay=0.000000)
Sending packet #128, rf path 0, return 0
status -> 4:2:
TX finished
INFO: tx_start_delay=1495 (1495.500000) - (1497, bw_delay=1.500000, notch_delay=0.000000)
Sending packet #129, rf path 0, return 0
status -> 4:2:
TX finished
INFO: tx_start_delay=1495 (1495.500000) - (1497, bw_delay=1.500000, notch_delay=0.000000)
Sending packet #130, rf path 0, return 0
status -> 4:2:
TX finished
INFO: tx_start_delay=1495 (1495.500000) - (1497, bw_delay=1.500000, notch_delay=0.000000)
Sending packet #131, rf path 0, return 0
status -> 4:2:
TX finished
INFO: tx_start_delay=1495 (1495.500000) - (1497, bw_delay=1.500000, notch delay=0.000000)
Sending packet #132, rf path 0, return 0
status -> 4:2:
TX finished
```

#### 4. High temperature test chart:



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### 5. Low temperature test chart:





# 7. Version update

| Version Number | Date       | Modifies the content | Author |
|----------------|------------|----------------------|--------|
| V1.0           | 2018-06-21 | Create the document  | Farce  |